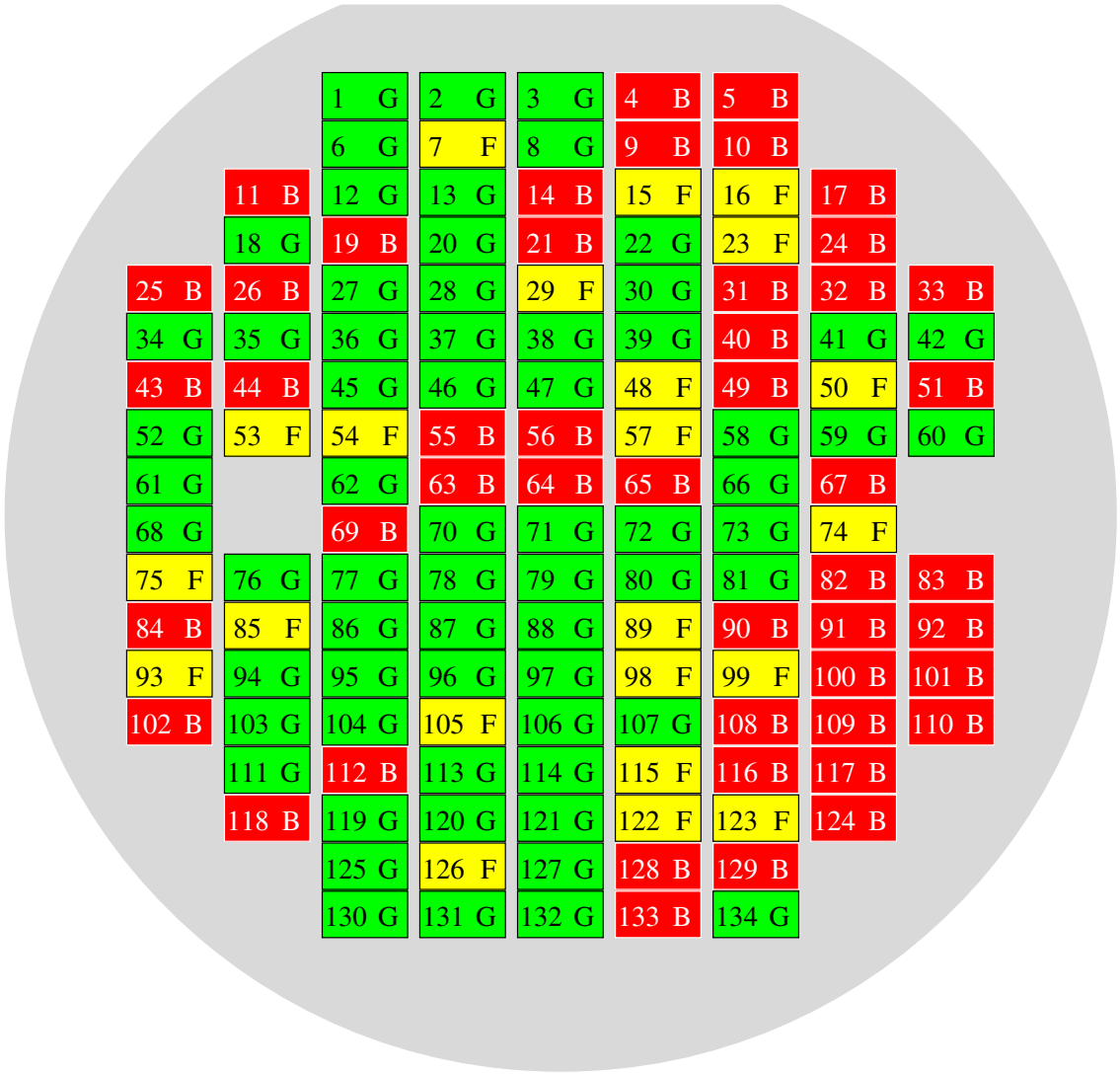
Die quality map for wafer 238 s/n: 21316-16-13

Date: 12/17/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged